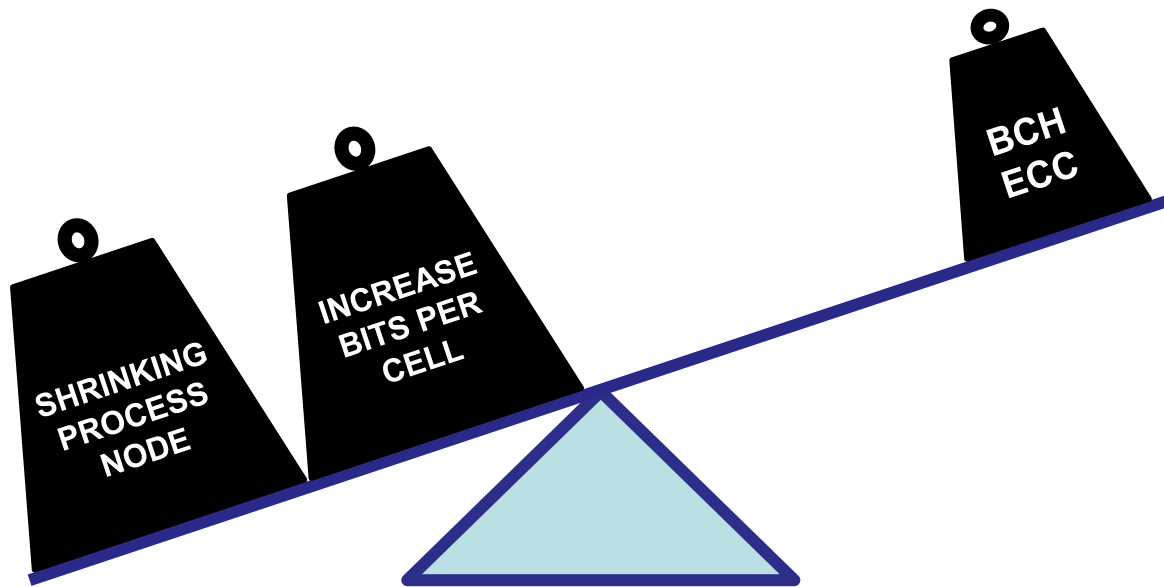


Controller IC Evaluation of High Radix Parity Check Code

Oliver Hambrey
Siglead Europe Limited

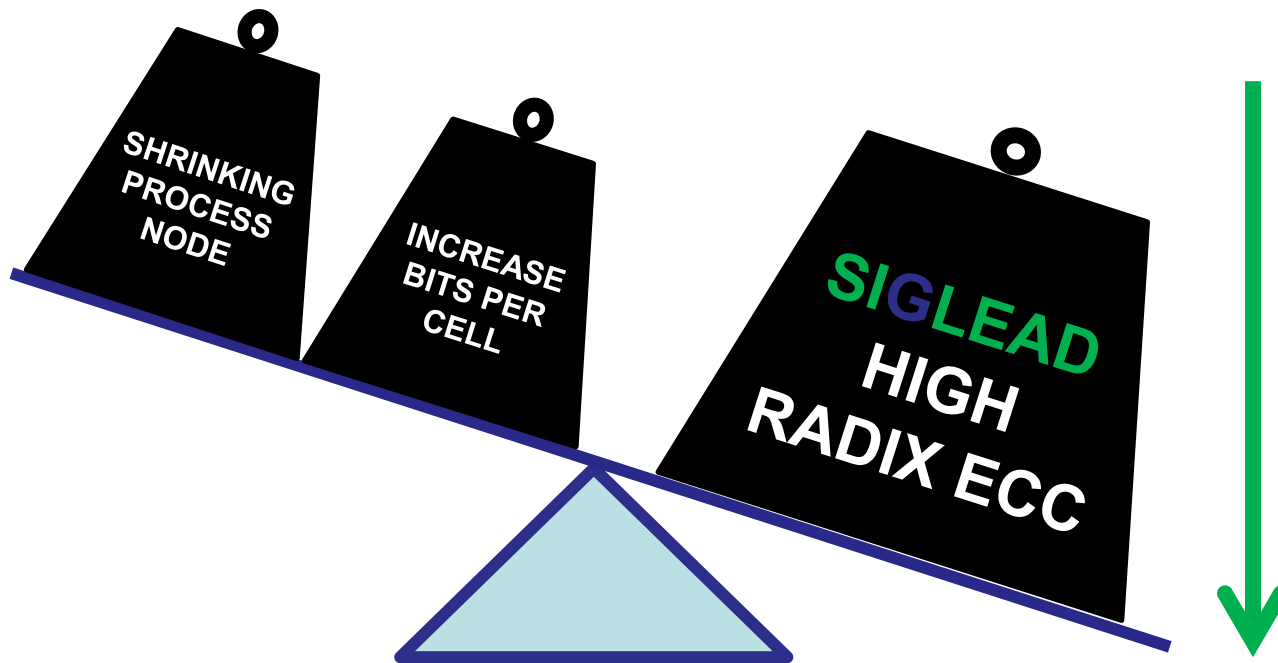
NAND vs Error Correction (1)



NAND raw bit error rate increases.

Conventional BCH ECC cannot protect data.

NAND vs Error Correction (2)



A stronger
ECC will
protect the
data.

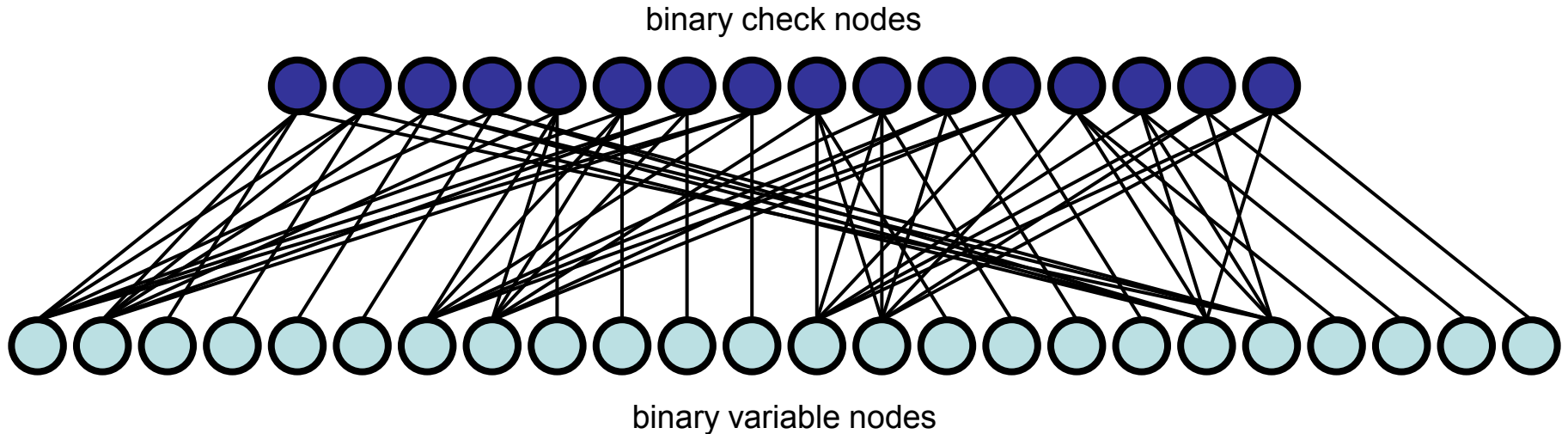
The balance is
tipped in our
favor!

Siglead's High Radix ECC

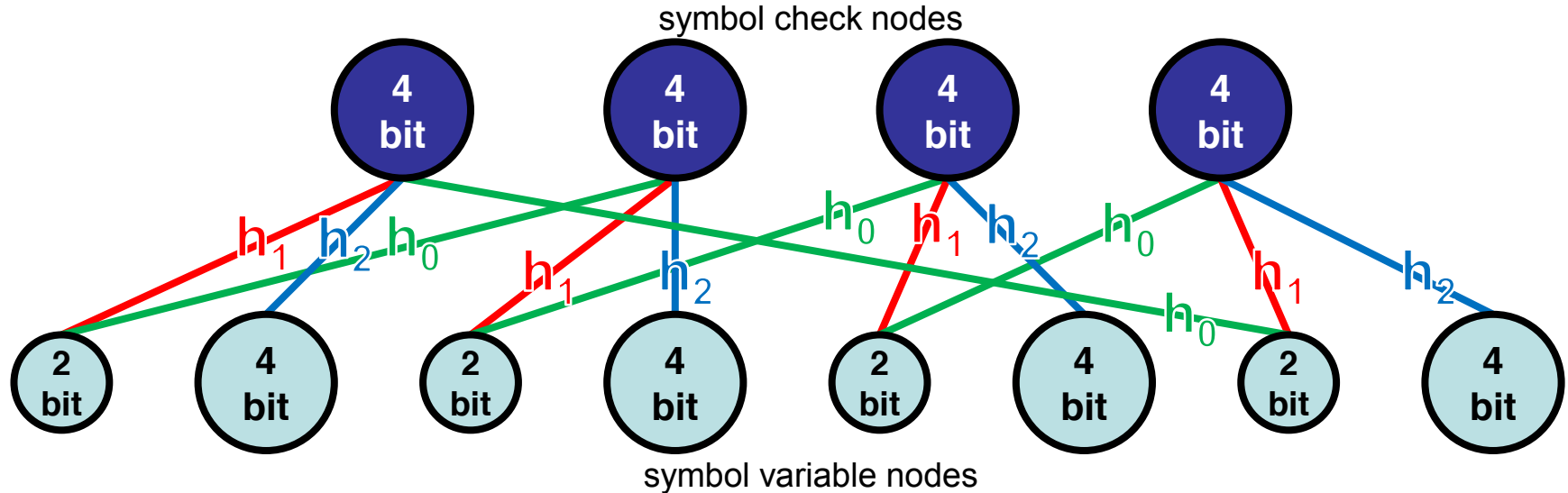
- High Radix ECC is in our SATAIII Controller IC
- Significantly stronger than BCH ECC
 - typically delivering at least 2x improvement in SSD endurance even on sub 20nm TLC nodes
- No significant compromise in power consumption and throughput



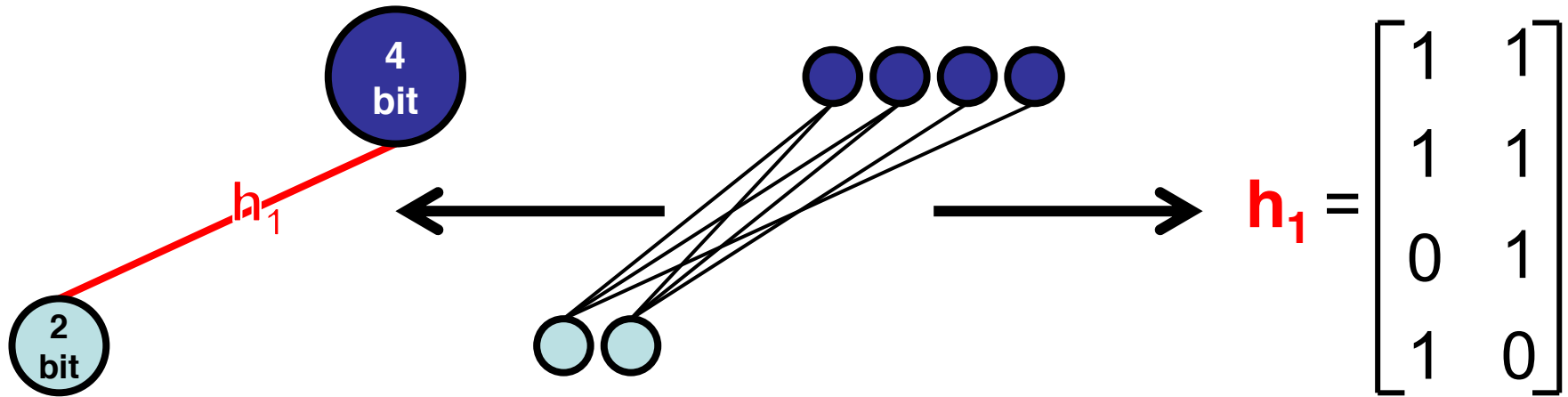
- Merge binary variable/check nodes of a binary ECC



- Merge binary variable/check nodes of a binary ECC...
...to get variable/check node SYMBOLS + **EDGE LABELS**



- Edge label is matrix representation of merged edges of binary ECC

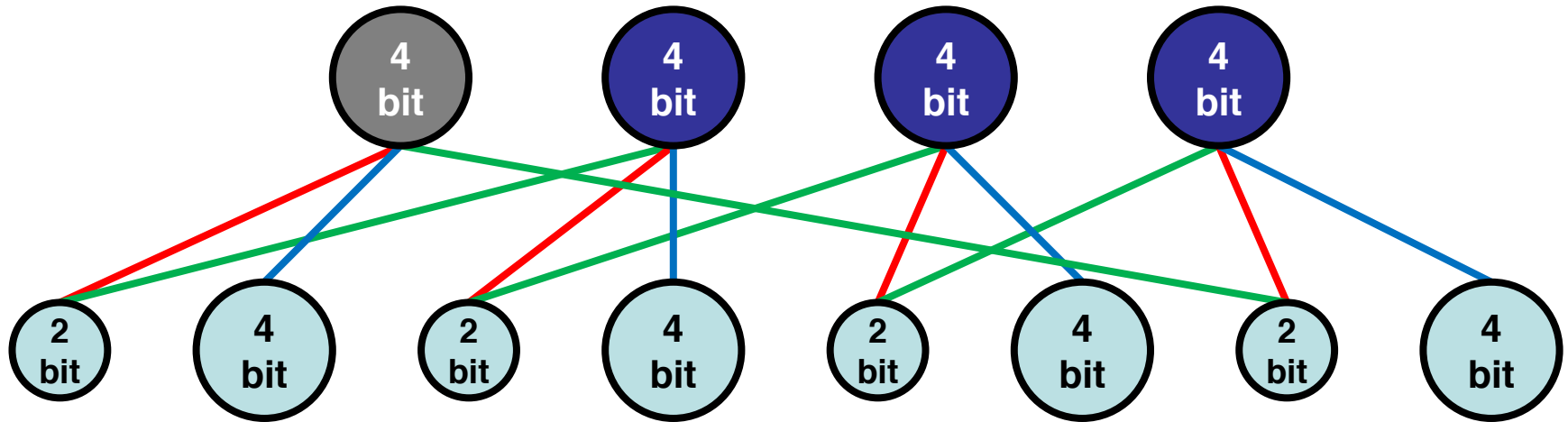


- High Radix ECC parity check matrix is a matrix of sub-matrices

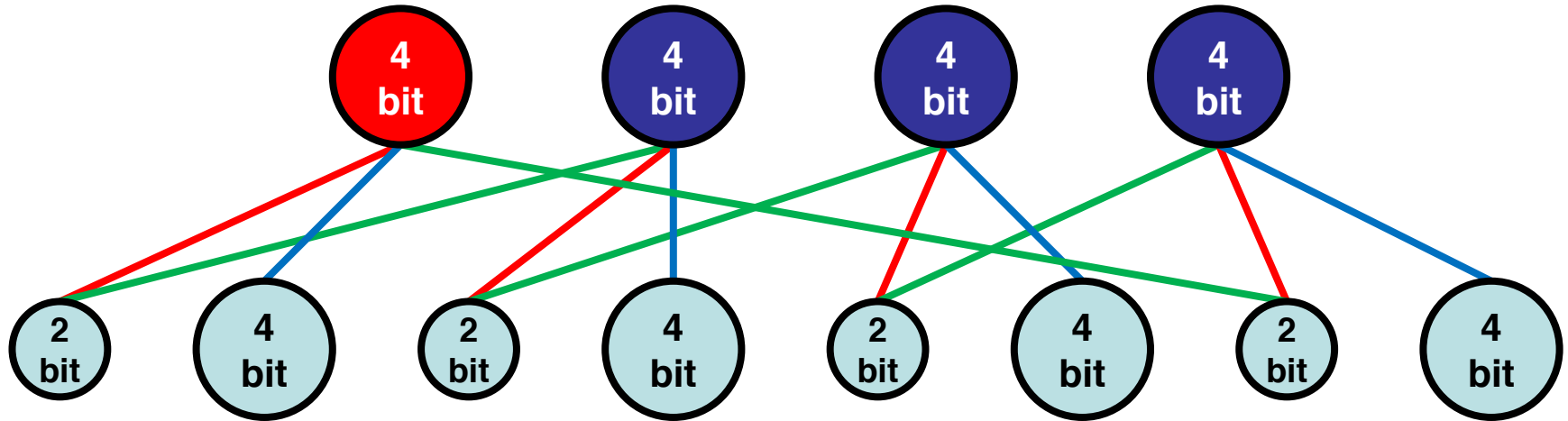
$$H = \begin{bmatrix} h_1 & h_2 & 0 & 0 & 0 & 0 & h_0 & 0 \\ h_0 & 0 & h_1 & h_2 & 0 & 0 & 0 & 0 \\ 0 & 0 & h_0 & 0 & h_1 & h_2 & 0 & 0 \\ 0 & 0 & 0 & 0 & h_0 & 0 & h_1 & h_2 \end{bmatrix}$$

$$\text{where } h_0 = \begin{bmatrix} 0 & 1 \\ 1 & 0 \\ 1 & 1 \\ 1 & 1 \end{bmatrix}, \quad h_1 = \begin{bmatrix} 1 & 1 \\ 1 & 1 \\ 0 & 1 \\ 1 & 0 \end{bmatrix} \quad \text{and} \quad h_2 = \begin{bmatrix} 1 & 0 & 0 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 1 \end{bmatrix}$$

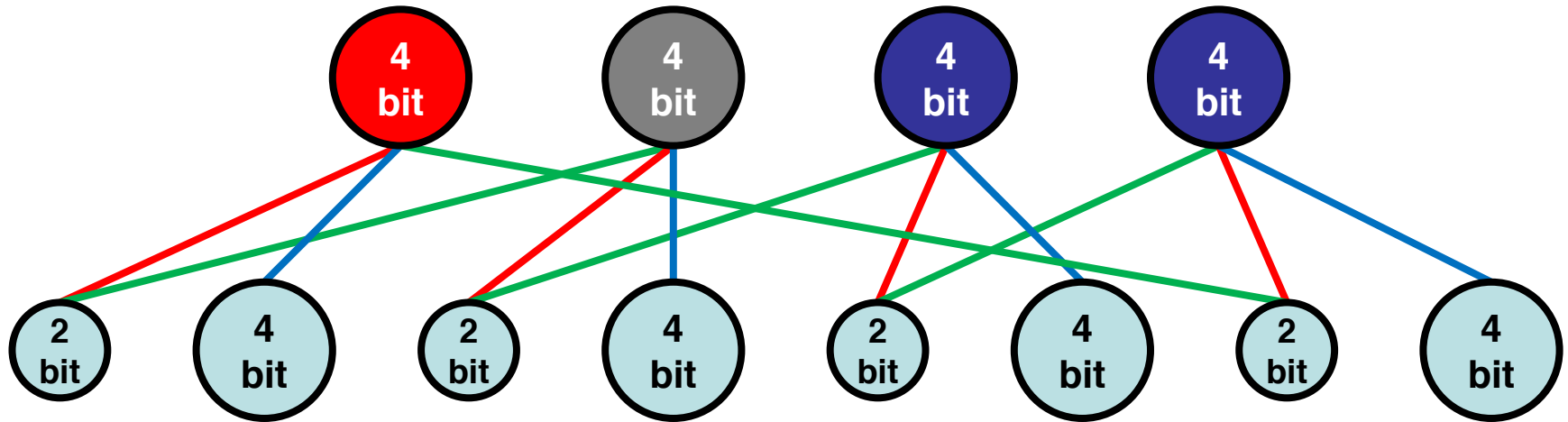
- Start with 1st check node (highlighted grey)



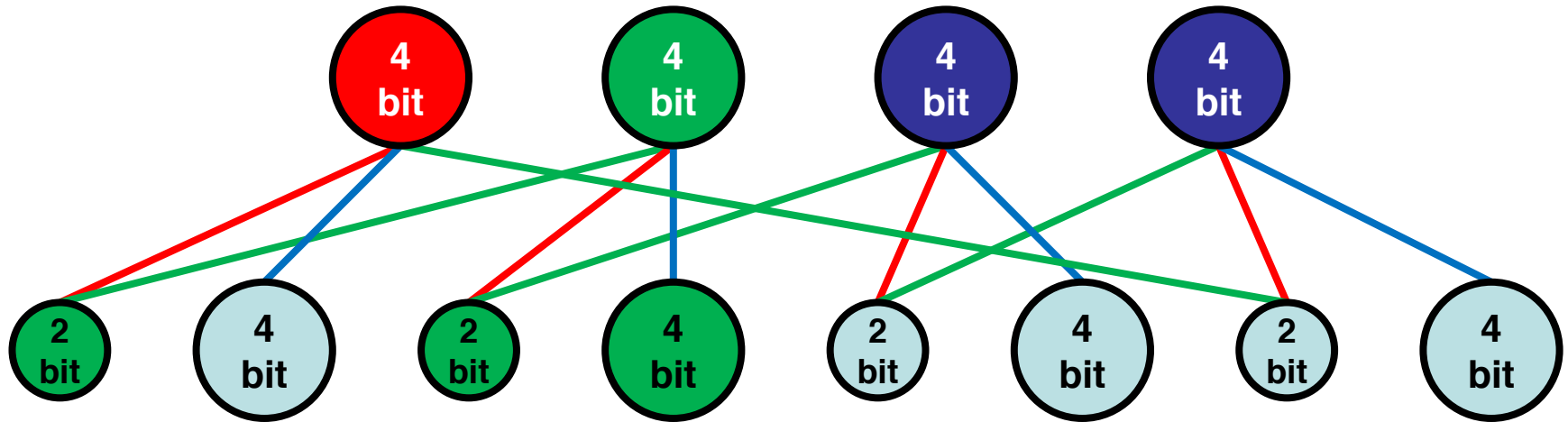
- 1st check node ECC uncorrectable (highlight red)



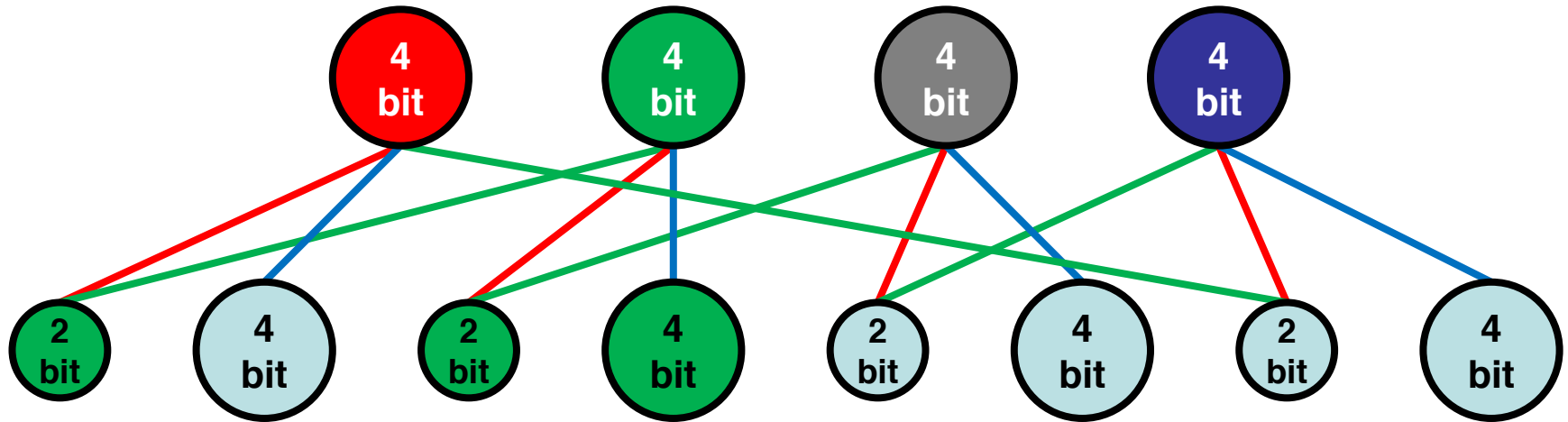
- Move to 2nd check node (highlighted grey)



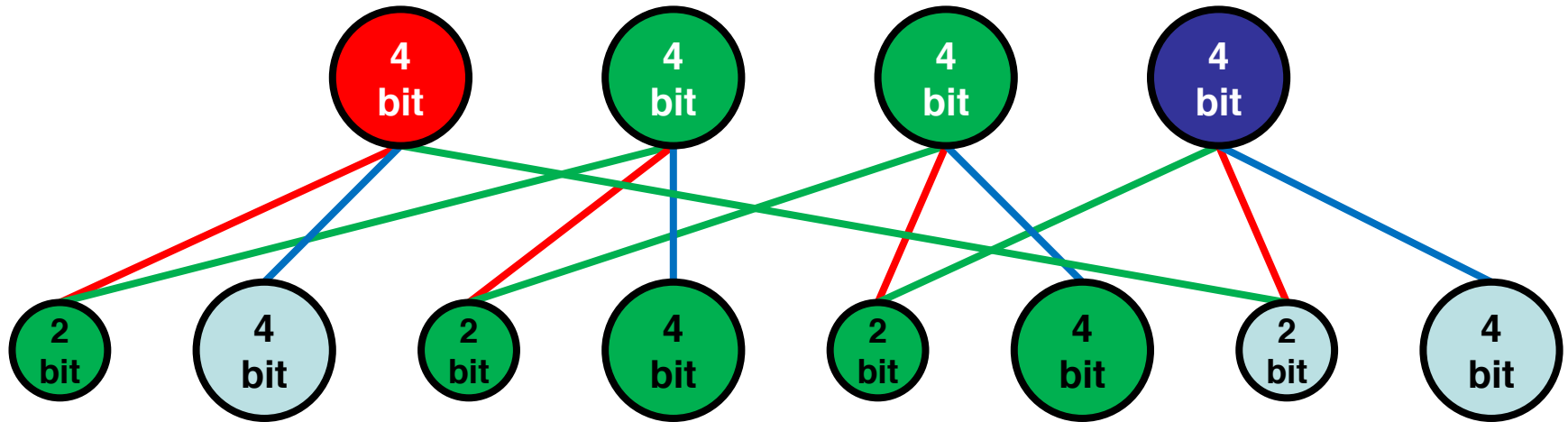
- 2nd check node ECC correctable (highlight green)
- Attached variable nodes are corrected (highlighted green)



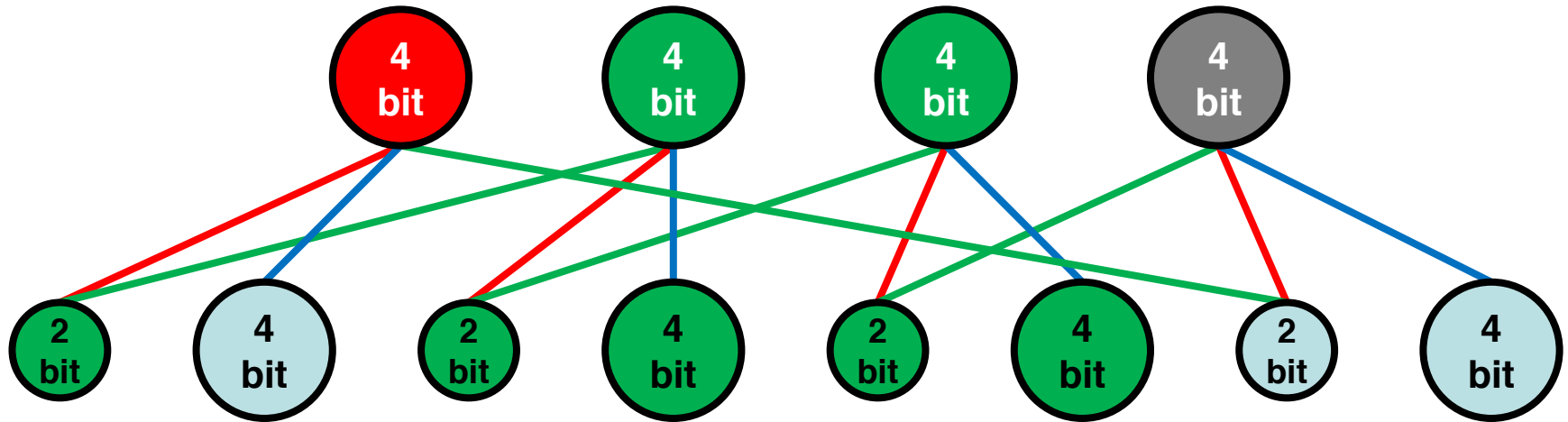
- Move to 3rd check node (highlighted grey)



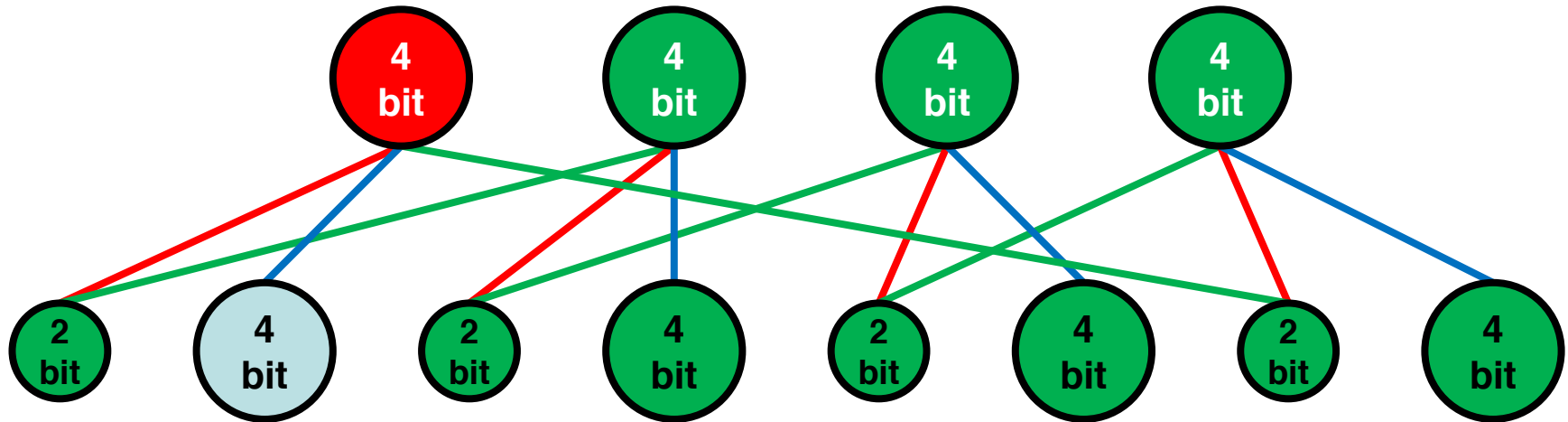
- 3rd check node ECC correctable (highlight green)
- Attached variable nodes are corrected (highlighted green)



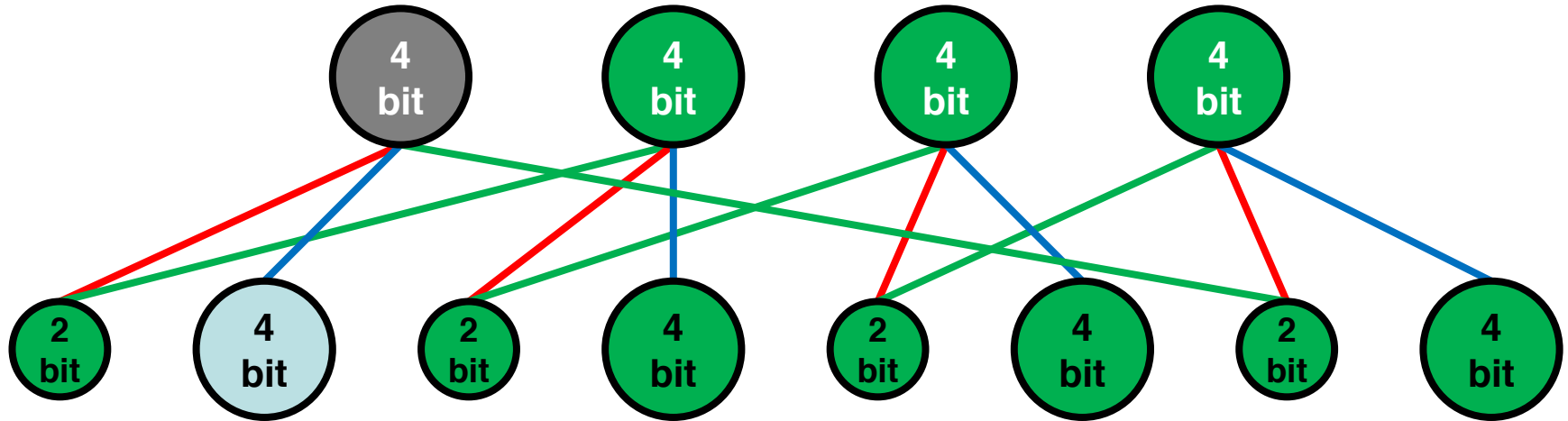
- Move to 4th check node (highlighted grey)



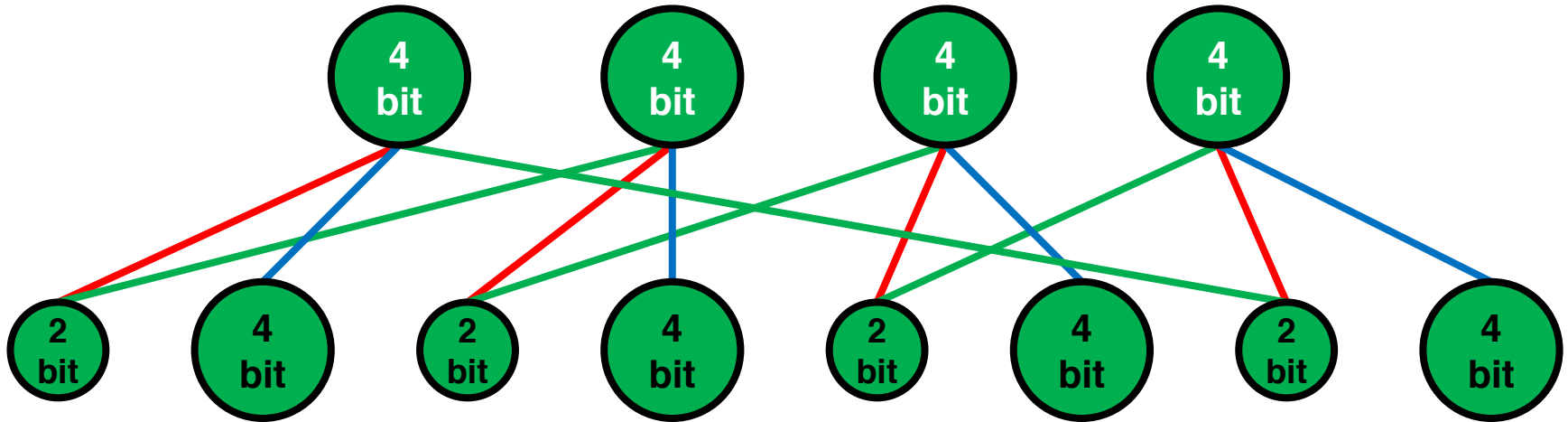
- 4th check node ECC correctable (highlight green)
- Attached variable nodes are corrected (highlighted green)



- Return to 1st check node (highlighted grey)

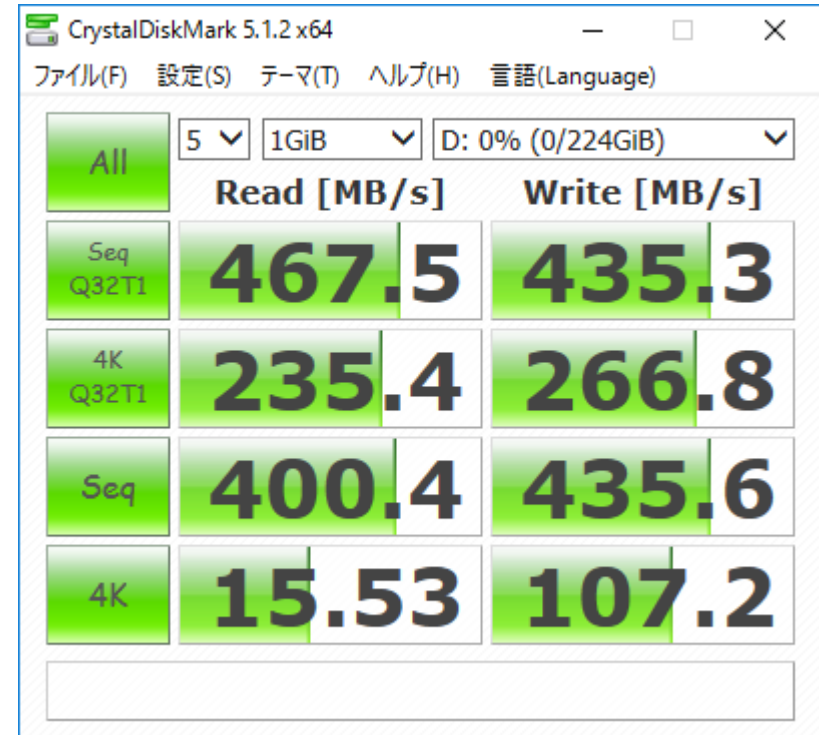


- 1st check node ECC is now correctable (highlight green)
- Attached variable nodes are corrected (highlighted green)



Controller IC Throughput Performance

- Throughput performance of Siglead's controller IC with High Radix ECC enabled
- **INTERFACE:** SATAIII
- No significant drop down in performance when using High Radix ECC



Controller ECC Performance on Sub 20nm TLC NAND

- Controller IC evaluation of High Radix ECC
- **NAND:** sub 20nm TLC
- **ENDURANCE:** 300P/E cycles using “LDPC achieving RBER=10⁻²”
- High Radix ECC achieves endurance of up to 600P/E cycles

SIGLEAD’S High Radix ECC achieved 2x ENDURANCE on sub 20nm TLC node

SUB 20nm TLC NAND		
P/E CYCLES	BCH CODE ONLY	SIGLEAD HIGH RADIX ECC
150	FAIL	PASS
300	FAIL	PASS
450	FAIL	PASS
600	FAIL	PASS
750	FAIL	FAIL

VISIT SIGLEAD'S BOOTH @ FMS2016

Live demo of SL2007D – our SSD controller IC

Live Demo of our NAND analyzer platforms
SigNASII and SigNAS3

BOOTH 900